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Fairchild Semiconductor NDT456P

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Datasheet of NDT456P - MOSFET P-CH 30V 7.5A SOT-223-4

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December 1998

P-Channel Enhancement Mode Field Effect Transistor

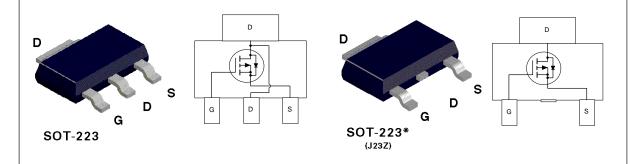
General Description

NDT456P

Power SOT P-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, high cell density, DMOS technology. This very high density process is especially tailored to minimize on-state resistance and provide superior switching performance. These devices are particularly suited for low voltage applications such as notebook computer power management, battery powered circuits, and DC motor control.

Features

- = -7.5 A, -30 V. $R_{DS(ON)}$ = 0.030 Ω @ V_{GS} = -10 V $R_{DS(ON)}$ = 0.045 Ω @ V_{GS} = -4.5 V.
- High density cell design for extremely low R_{DS(ON)}.
- High power and current handling capability in a widely used surface mount package.



Absolute Maximum Ratings T_A = 25°C unless otherwise noted

Symbol	Parameter		NDT456P	Units
DSS	Drain-Source Voltage		-30	V
GSS	Gate-Source Voltage		±20	V
	Drain Current - Continuous	(Note 1a)	±7.5	A
	- Pulsed		±20	
)	Maximum Power Dissipation	(Note 1a)	3	W
		(Note 1b)	1.3	
		(Note 1c)	1.1	
T _{STG}	Operating and Storage Temperature Range		-65 to 150	°C
HERMA	AL CHARACTERISTICS			
θJA	Thermal Resistance, Junction-to-Ambient (Note 1a)		42	°C/W
enc enc	Thermal Resistance, Junction-to-Case (Note 1)		12	°C/W

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Symbol	Parameter	Conditions		Min	Тур	Max	Units
OFF CHA	RACTERISTICS						
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_{D} = 250 \mu\text{A}$		-30			V
I _{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = -24 \text{ V}, V_{GS} = 0 \text{ V}$				-1	μΑ
			T _J = 55°C			-10	μΑ
I _{GSSF}	Gate - Body Leakage, Forward	$V_{GS} = 20 \text{ V}, V_{DS} = 0 \text{ V}$				100	nA
I _{GSSR}	Gate - Body Leakage, Reverse	$V_{GS} = -20 \text{ V}, V_{DS} = 0 \text{ V}$				-100	nA
ON CHAR	ACTERISTICS (Note 2)						_
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = -250 \mu\text{A}$		-1	-1.5	-3	V
			T _J = 125°C	-0.5	-1.1	-2.6	
R _{DS(ON)}	Static Drain-Source On-Resistance	$V_{GS} = -10 \text{ V}, I_{D} = -7.5 \text{ A}$			0.026	0.03	Ω
			T _J = 125°C		0.035	0.054	
		$V_{GS} = -4.5 \text{ V}, I_{D} = -6 \text{ A}$			0.041	0.045	
I _{D(on)}	On-State Drain Current	$V_{GS} = -10 \text{ V}, V_{DS} = -5 \text{ V}$		-20			Α
		$V_{GS} = -4.5 \text{ V}, V_{DS} = -5 \text{ V}$		-10			
G _{fs}	Forward Transconductance	$V_{GS} = -10 \text{ V}, I_{D} = -7.5 \text{ A}$			13		S
DYNAMIC	CHARACTERISTICS						
C _{iss}	Input Capacitance	$V_{DS} = -15 \text{ V}, V_{GS} = 0 \text{ V},$ f = 1.0 MHz			1440		pF
Coss	Output Capacitance				905		pF
C _{rss}	Reverse Transfer Capacitance				355		pF
SWITCHIN	IG CHARACTERISTICS (Note 2)						
t _{D(on)}	Turn - On Delay Time	$V_{DD} = -15 \text{ V}, I_{D} = -7 \text{ A},$ $V_{GEN} = -10 \text{ V}, R_{GEN} = 12 \Omega$			10	20	ns
t,	Turn - On Rise Time				65	120	ns
$\mathbf{t}_{D(off)}$	Turn - Off Delay Time				70	130	ns
t,	Turn - Off Fall Time				70	130	ns
Q_g	Total Gate Charge	$V_{DS} = -10 \text{ V},$ $I_{D} = -7.5 \text{ A}, V_{GS} = -10 \text{ V}$			47	67	nC
Q_{gs}	Gate-Source Charge				5		nC
Q_{gd}	Gate-Drain Charge				12		nC



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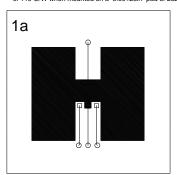
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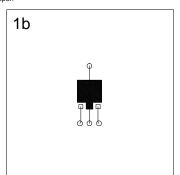
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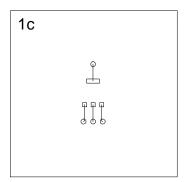
Electrical Characteristics (T _A = 25°C unless otherwise noted)							
Symbol	Parameter	Conditions		Тур	Max	Units	
DRAIN-SOURCE DIODE CHARACTERISTICS AND MAXIMUM RATINGS							
I _s	Maximum Continuous Drain-Source Diode Forward Current				-2.5	Α	
V _{SD}	Drain-Source Diode Forward Voltage	$V_{GS} = 0 \text{ V}, I_{S} = -2.5 \text{ A} \text{ (Note 2)}$		- 0.85	-1.2	V	
t _{rr}	Reverse Recovery Time	$V_{GS} = 0 \text{ V}, I_F = -2.5 \text{ A } dI_F/dt = 100 \text{ A/}\mu\text{s}$			140	ns	

Notes

- votes:
 1. $P_D(t) = \frac{T_J T_A}{R_{BJA}(t)} = \frac{T_J T_A}{R_{BJA}(t)} = I_D^2(t) \times R_{DS(ON) \oplus T_J} R_{_{BJA}}$ is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. $R_{_{BJC}}$ is guaranteed by design while $R_{_{BCA}}$ is defined by users. For general reference: Applications on 4.5°x5° FR-4 PCB under still air environment, typical $R_{_{BJA}}$ is found to be:
 - a. 42°C when mounted on a 1 in² pad of 2oz copper.
 - b. 95°C when mounted on a 0.066in² pad of 2oz copper.
 - c. 110°C/W when mounted on a 0.00123in² pad of 2oz copper.







Scale 1 : 1 on letter size paper

2. Pulse Test: Pulse Width \leq 300 μ s, Duty Cycle \leq 2.0%.

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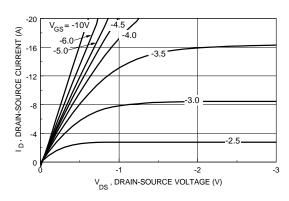


Figure 1. On-Region Characteristics.

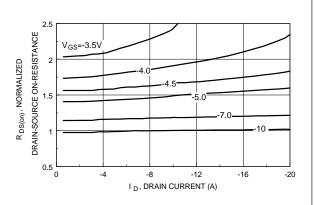


Figure 2. On-Resistance Variation with Gate Voltage and Drain Current.

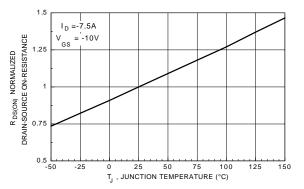


Figure 3. On-Resistance Variation with Temperature.

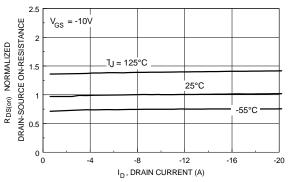


Figure 4. On-Resistance Variation with Drain Current and Temperature.

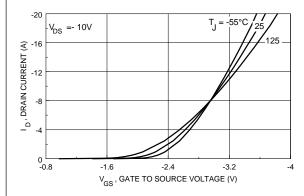


Figure 5. Transfer Characteristics.

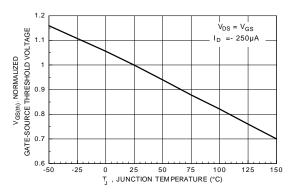


Figure 6. Gate Threshold Variation with Temperature.



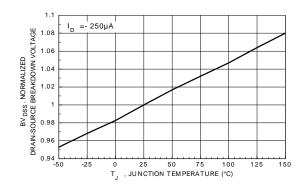


Figure 7. Breakdown Voltage Variation with Temperature.

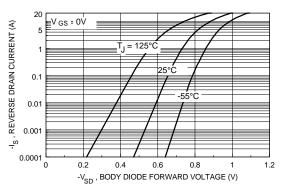


Figure 8. Body Diode Forward Voltage Variation with Current and Temperature.

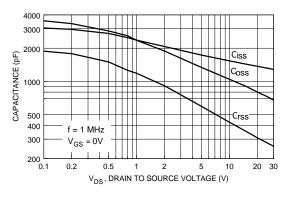


Figure 9. Capacitance Characteristics.

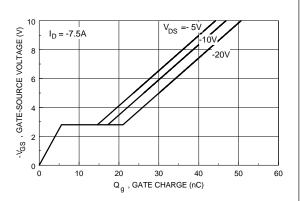


Figure 10. Gate Charge Characteristics.

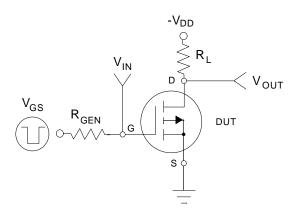


Figure 11. Switching Test Circuit.

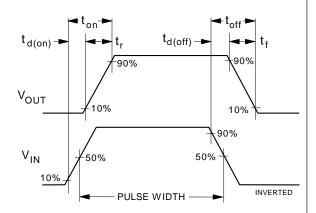
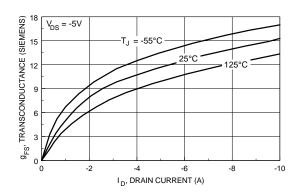


Figure 12. Switching Waveforms.

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Typical Thermal Characteristics



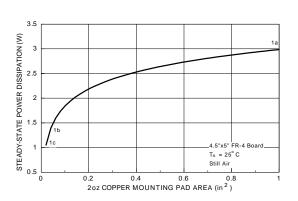
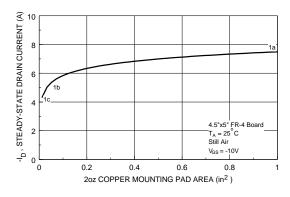


Figure 13. Transconductance Variation with Drain Current and Temperature.

Figure 14. SOT-223 Maximum Steady-State Power Dissipation versus Copper Mounting Pad Area.



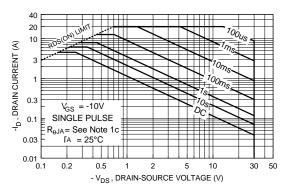


Figure 15. Maximum Steady-State Drain Current versus Copper Mounting Pad Area.

Figure 16. Maximum Safe Operating Area.

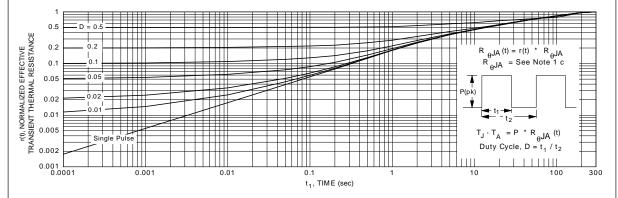


Figure 17. Transient Thermal Response Curve.

Note: Thermal characterization performed using the conditions described in note 1c. Transient thermal response will change depending on the circuit board design.



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